

<b>Notice of References Cited</b>	Application/Control No. 10/541,678		Applicant(s)/Patent Under Reexamination KUNITANI ET AL.	
	Examiner Hiep Nguyen		Art Unit 2816	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0071698	04-2006	Parikh, Parag	327/231
*	B	US-2002/0140472	10-2002	Sonobe, Hiroshi	327/158
*	C	US-2006/0202729	09-2006	Gomm et al.	327/231
*	D	US-6,342,796	01-2002	Jung, Hea-Suk	327/141
*	E	US-6,437,618	08-2002	Lee, Seong-Hoon	327/158
*	F	US-6,603,337	08-2003	Cho, Seong Ik	327/149
*	G	US-6,825,644	11-2004	Kernahan et al.	323/283
*	H	US-6,985,016	01-2006	Chow et al.	327/149
*	I	US-7,027,548	04-2006	Palusa et al.	375/375
*	J	US-7,091,760	08-2006	Chang et al.	327/158
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.